



**ALPHA & OMEGA**  
SEMICONDUCTOR



## AO4604

### Complementary Enhancement Mode Field Effect Transistor

#### General Description

The AO4604 uses advanced trench technology MOSFETs to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs may be used in power inverters, and other applications. AO4604 and AO4604L are electrically identical.

-RoHS Compliant

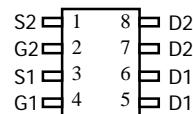
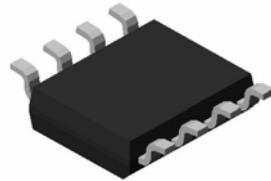
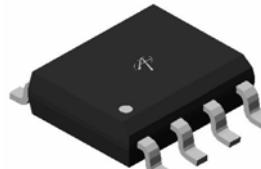
-AO4604L is Halogen Free

#### Features

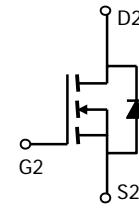
n-channel	p-channel
$V_{DS}$ (V) = 30V	-30V
$I_D = 6.9A$ ( $V_{GS}=10V$ )	-5A ( $V_{GS} = -10V$ )
$R_{DS(ON)}$	$R_{DS(ON)}$
< 28mΩ ( $V_{GS}=10V$ )	< 52mΩ ( $V_{GS} = -10V$ )
< 42mΩ ( $V_{GS}=4.5V$ )	< 87mΩ ( $V_{GS} = -4.5V$ )

**100% Rg Tested!**

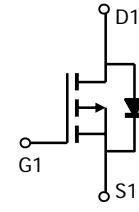
SOIC-8



SOIC-8



n-channel



p-channel

#### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$I_D$	6.9	-5	A
$T_A=70^\circ C$		5.8	-4.2	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30	-20	
Power Dissipation	$P_D$	2	2	W
$T_A=70^\circ C$		1.44	1.44	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	°C

#### Thermal Characteristics: n-channel and p-channel

Parameter	Symbol	Device	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	n-ch	48	62.5	°C/W
Steady-State		n-ch	74	110	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	n-ch	35	40	°C/W
Steady-State		p-ch	48	62.5	°C/W
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	p-ch	74	110	°C/W
Steady-State		p-ch	35	40	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	p-ch	48	62.5	°C/W

**N-CHANNEL: Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		0.004	1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			5	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.9	3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	20			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=6.9\text{A}$ $T_J=125^\circ\text{C}$		22.5	28	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=5.0\text{A}$		31.3	38	
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=6.9\text{A}$	34.5	42		$\text{m}\Omega$
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}$	10	15.4		S
$I_S$	Maximum Body-Diode Continuous Current			0.76	1	V
					3	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		680	820	pF
$C_{\text{oss}}$	Output Capacitance			102		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			77		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.2	2	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=6.9\text{A}$		13.84	17	nC
$Q_g(4.5\text{V})$	Total Gate Charge			6.74	8.1	nC
$Q_{\text{gs}}$	Gate Source Charge			1.82		nC
$Q_{\text{gd}}$	Gate Drain Charge			3.2		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=2.2\Omega, R_{\text{GEN}}=3\Omega$		4.6		ns
$t_r$	Turn-On Rise Time			4.1		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			20.6		ns
$t_f$	Turn-Off Fall Time			5.2		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=6.9\text{A}, dI/dt=100\text{A}/\mu\text{s}$		16.5	20	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=6.9\text{A}, dI/dt=100\text{A}/\mu\text{s}$		7.8		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

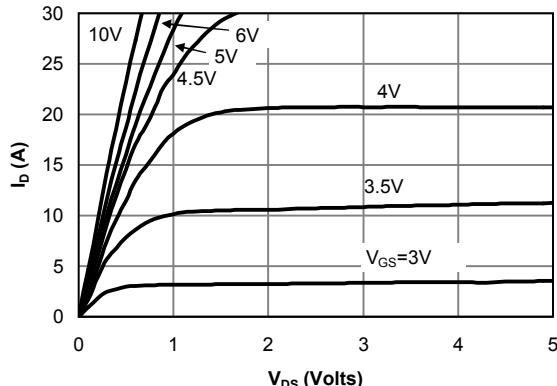
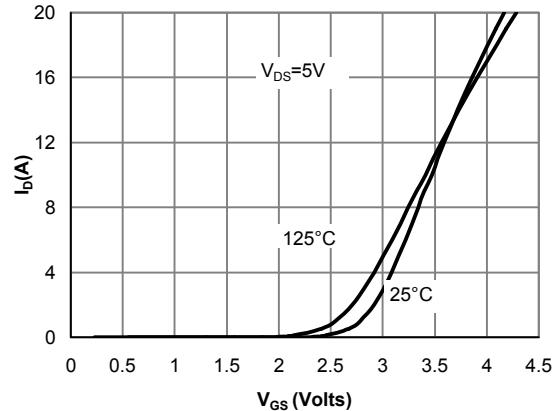
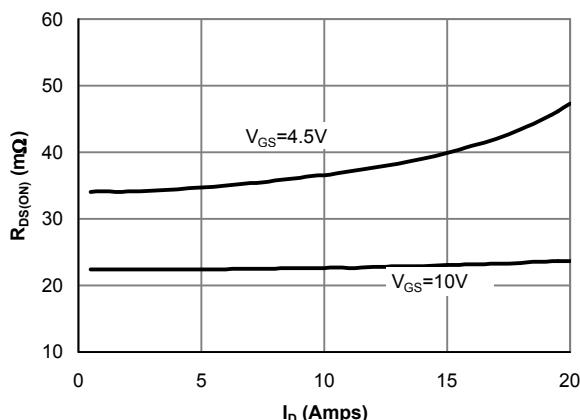
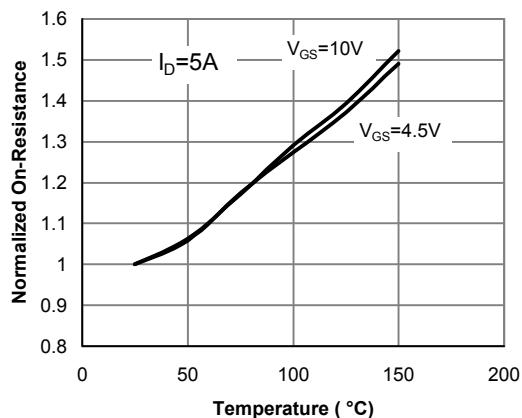
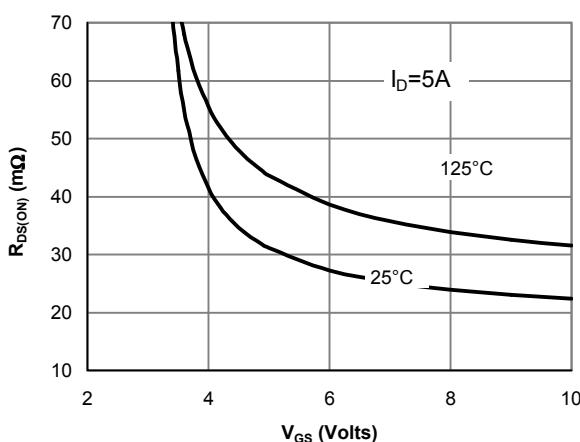
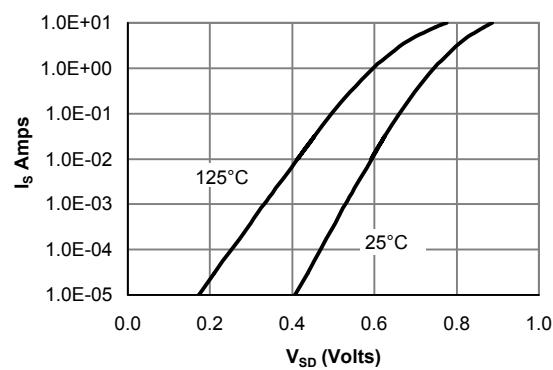
C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 80μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

Rev 4: Jan 2009

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE

**N-CHANNEL: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics**

**Figure 2: Transfer Characteristics**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**

**Figure 4: On-Resistance vs. Junction Temperature**

**Figure 5: On-Resistance vs. Gate-Source Voltage**

**Figure 6: Body diode characteristics**

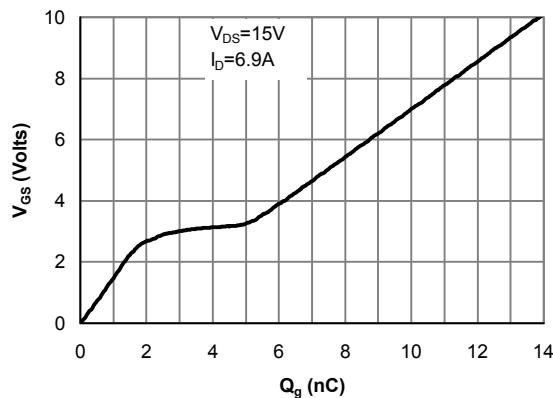
**N-CHANNEL: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 7: Gate-Charge characteristics

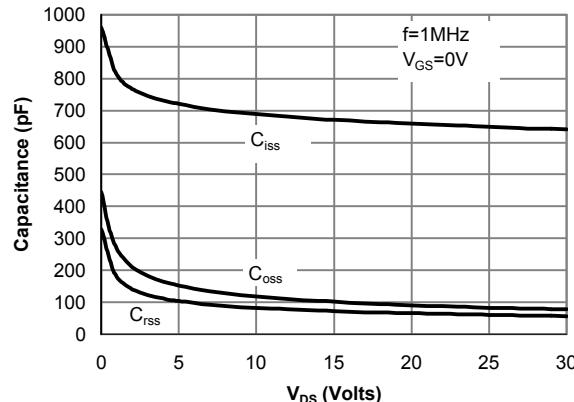


Figure 8: Capacitance Characteristics

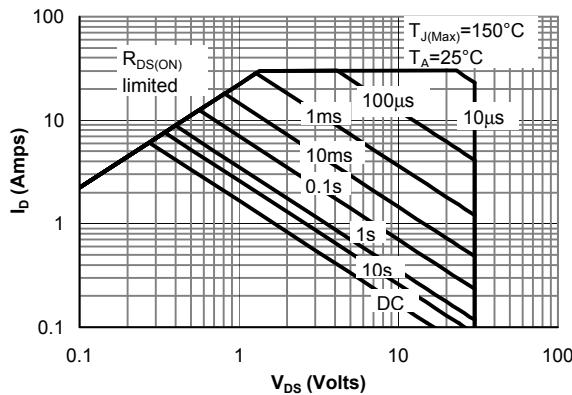


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

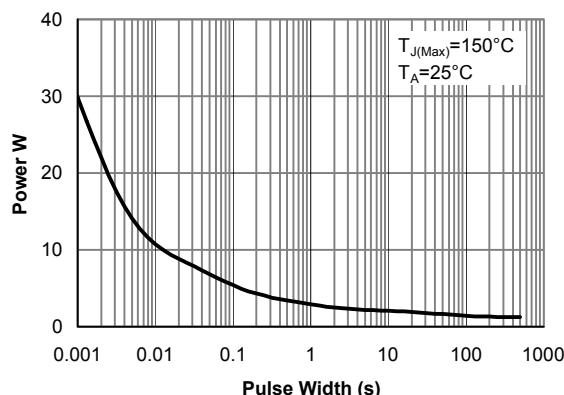


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

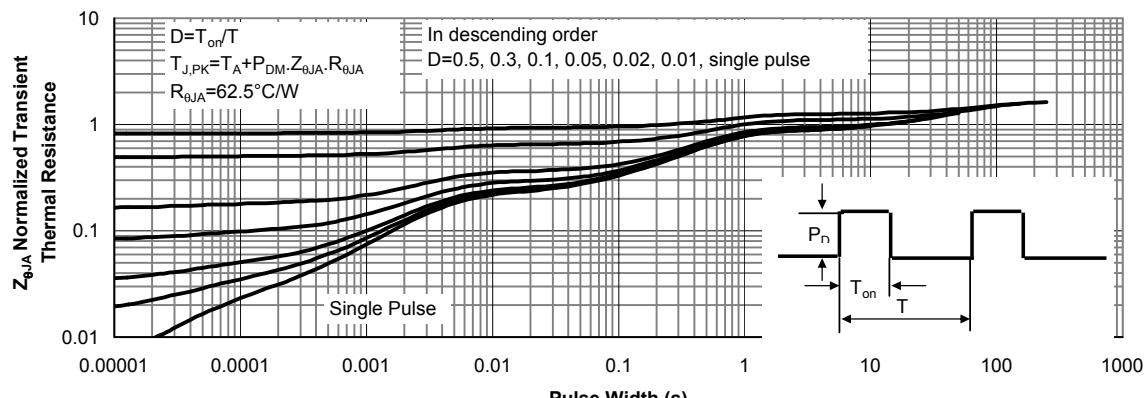
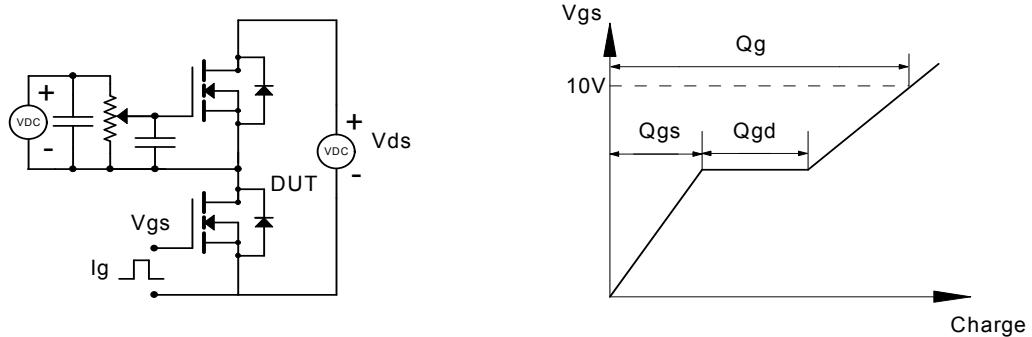
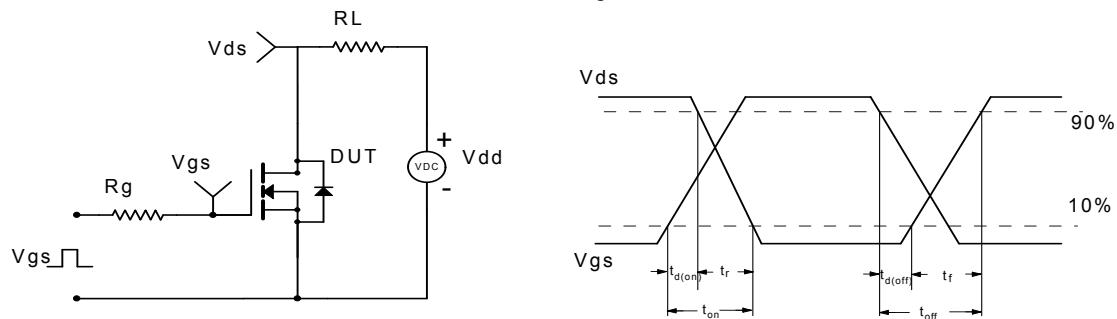
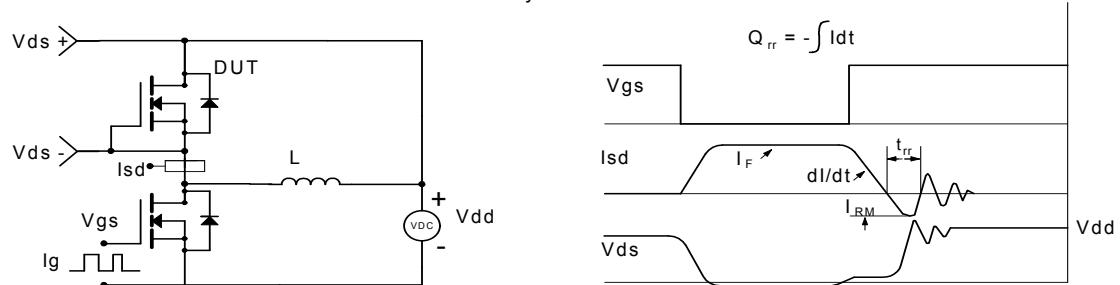


Figure 11: Normalized Maximum Transient Thermal Impedance

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**


---

**P-CHANNEL: Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1	-1.8	-3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-20			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-5\text{A}$ $T_J=125^\circ\text{C}$		39 54	52 70	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-4\text{A}$		67	87	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-5\text{A}$	6	8.6		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.77	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-2.8	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		700	900	pF
$C_{\text{oss}}$	Output Capacitance			120		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			75		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		10	15	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge (10V)	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-5\text{A}$		14.7	19	nC
$Q_g(4.5\text{V})$	Total Gate Charge (4.5V)			7.6	10	nC
$Q_{\text{gs}}$	Gate Source Charge			2		nC
$Q_{\text{gd}}$	Gate Drain Charge			3.8		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=3\Omega, R_{\text{GEN}}=3\Omega$		8.3		ns
$t_r$	Turn-On Rise Time			5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			29		ns
$t_f$	Turn-Off Fall Time			14		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		23.5	30	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		13.4		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leqslant 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

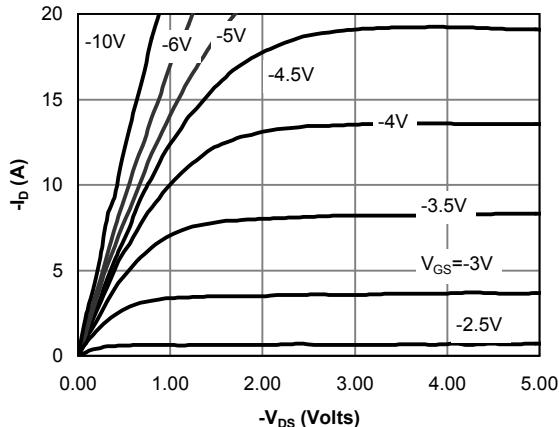
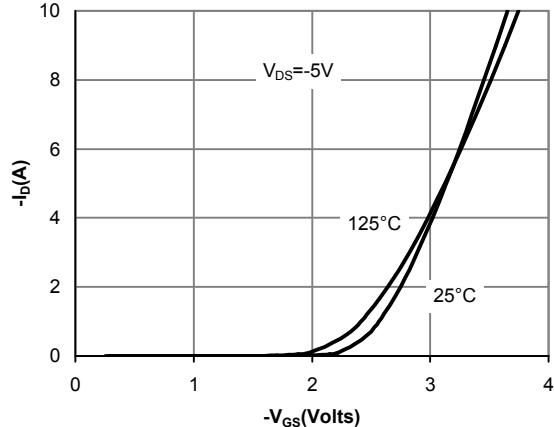
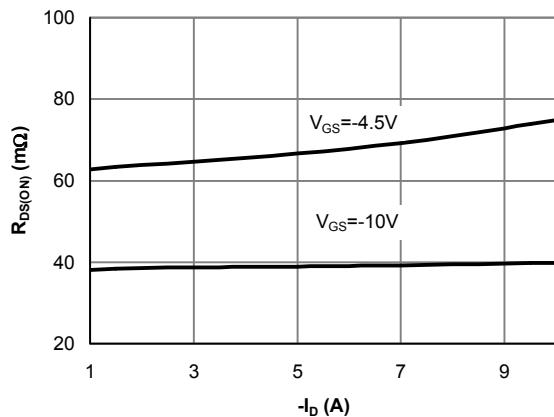
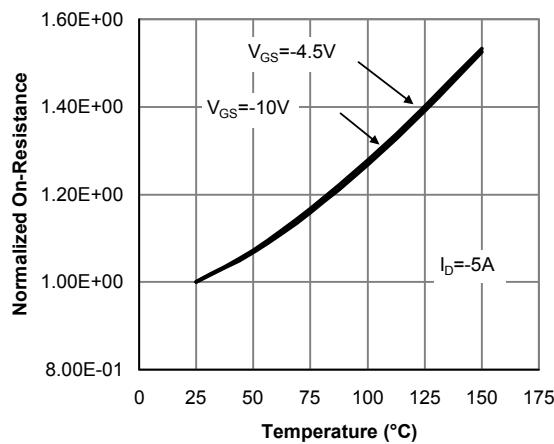
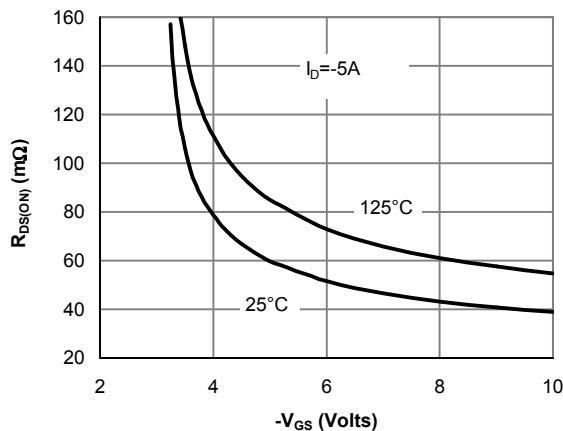
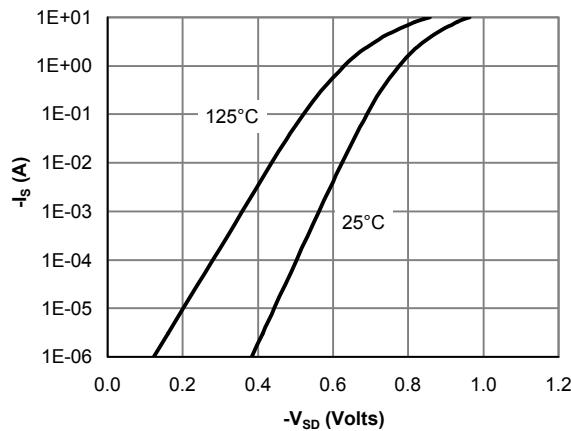
C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 $\mu\text{s}$  pulses, duty cycle 0.5% max.

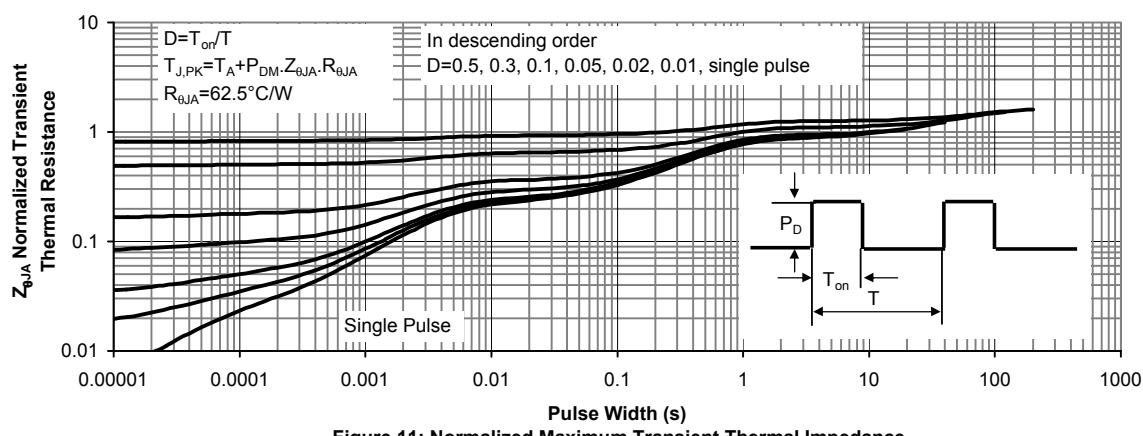
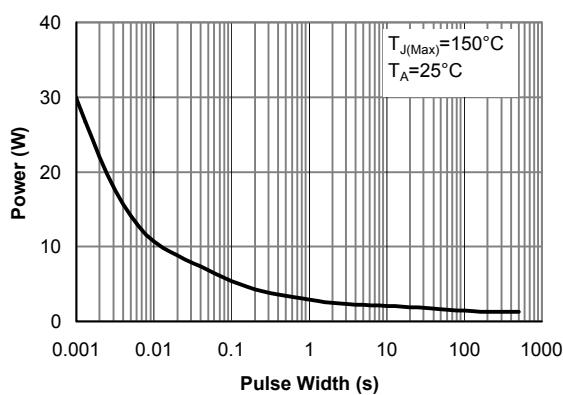
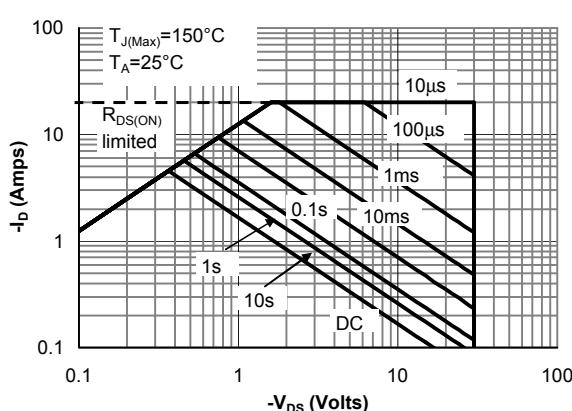
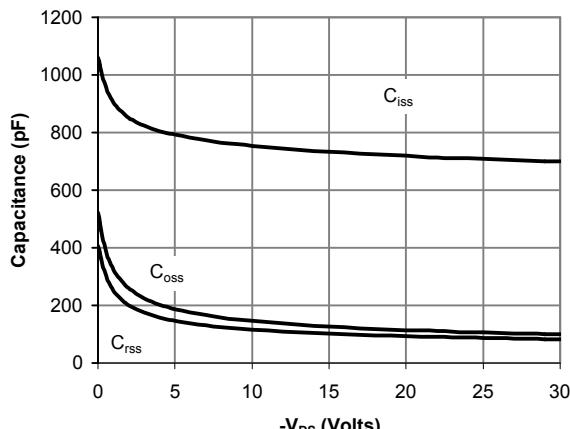
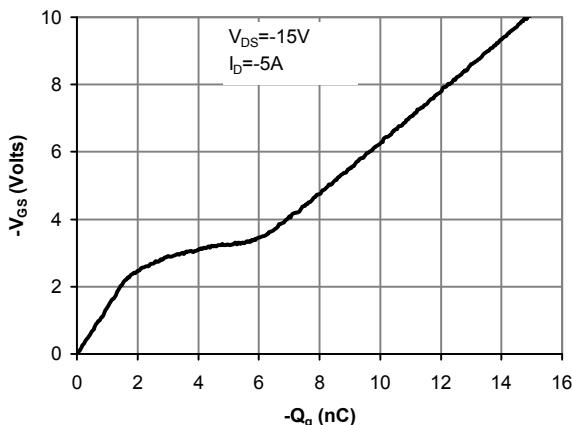
E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

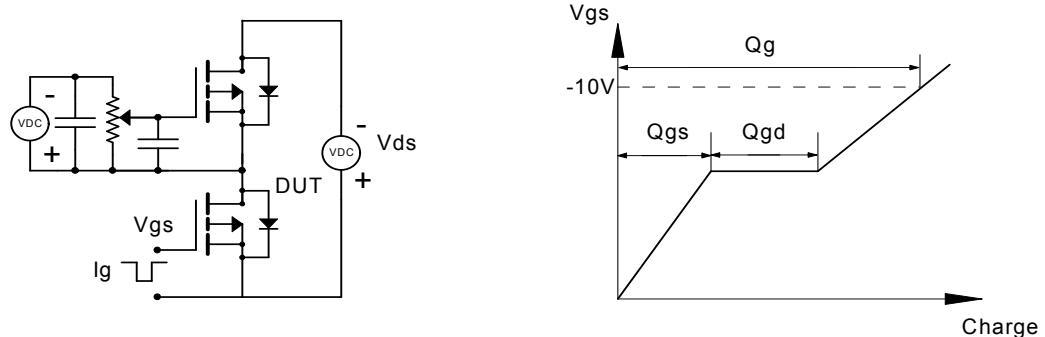
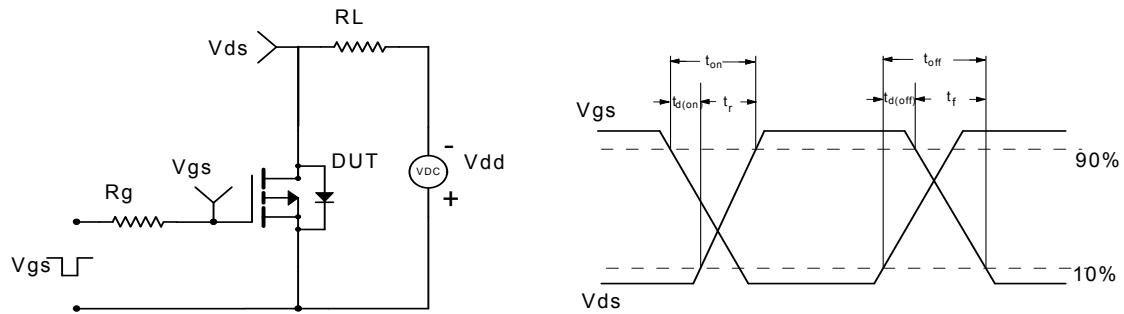
Rev 4: Jan 2009

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE

**P-CHANNEL: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 1: On-Region Characteristics**

**Figure 2: Transfer Characteristics**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**

**Figure 4: On-Resistance vs. Junction Temperature**

**Figure 5: On-Resistance vs. Gate-Source Voltage**

**Figure 6: Body-Diode Characteristics**

### P-CHANNEL: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
